

SSW4N60B / SSI4N60B

600V N-Channel MOSFET

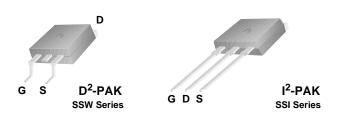
General Description

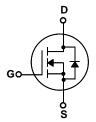
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies.

Features

- 4.0A, 600V, $R_{DS(on)}$ = 2.5 Ω @V_{GS} = 10 V Low gate charge (typical 22 nC)
- Low Crss (typical 14 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		SSW4N60B / SSI4N60B	Units	
V _{DSS}	Drain-Source Voltage		600	V	
I _D	Drain Current - Continuous (T _C = 25°C))	4.0	А	
	- Continuous (T _C = 100°C	C)	2.5	А	
I _{DM}	Drain Current - Pulsed	(Note 1)	16	Α	
V _{GSS}	Gate-Source Voltage		± 30	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	240	mJ	
I _{AR}	Avalanche Current	(Note 1)	4.0	А	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	10	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns	
P_{D}	Power Dissipation (T _A = 25°C) *		3.13	W	
	Power Dissipation (T _C = 25°C)		100	W	
	- Derate above 25°C		0.8	W/°C	
T _J , T _{stg}	Operating and Storage Temperature Range	е	-55 to +150	°C	
T _L	Maximum lead temperature for soldering p	urposes,	300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.25	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	3	Min	Тур	Max	Units
Off Cha	racteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		600			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced	l to 25°C		0.65		V/°C
I _{DSS}	Zana Oata Walta na Basin Oamant	V _{DS} = 600 V, V _{GS} = 0 V				10	μΑ
	Zero Gate Voltage Drain Current	V _{DS} = 480 V, T _C = 125°C)			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 2.0 A			2.0	2.5	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 2.0 A	(Note 4)		4.7		S
	ic Characteristics					Г	
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$			710	920	pF
Coss	Output Capacitance	f = 1.0 MHz			65	85	pF
C _{rss}	Reverse Transfer Capacitance				14	19	pF
Switchi	ng Characteristics						
t _{d(on)}	Turn-On Delay Time	V _{DD} = 300 V, I _D = 4.0 A,			20	50	ns
t _r	Turn-On Rise Time	$V_{DD} = 300 \text{ V}, I_D = 4.0 \text{ A},$ $R_G = 25 \Omega$			55	120	ns
t _{d(off)}	Turn-Off Delay Time	g			70	150	ns
t _f	Turn-Off Fall Time		(Note 4, 5)		55	120	ns
Qg	Total Gate Charge	V _{DS} = 480 V, I _D = 4.0 A,			22	29	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V			4.8		nC
Q _{gd}	Gate-Drain Charge		(Note 4, 5)		8.5		nC
Drain-S	ource Diode Characteristics ar	nd Maximum Rating	s				
I _S	Maximum Continuous Drain-Source Did					4.0	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	orward Current				16	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 4.0 \text{ A}$				1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 4.0 \text{ A},$			330		ns
Q _{rr}	Reverse Recovery Charge	dI _F / dt = 100 A/μs	(Note 4)		2.67		μС

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 27.5mH, I_{AS} = 4.0A, V_{DD} = 50V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} ≤ 4.0A, di/dt ≤ 300A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

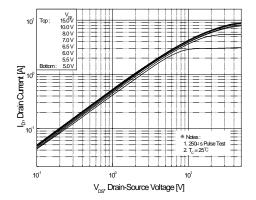


Figure 1. On-Region Characteristics

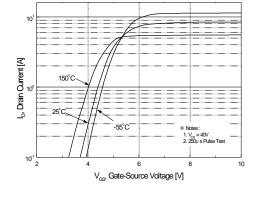


Figure 2. Transfer Characteristics

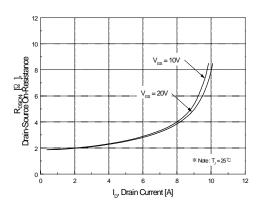


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

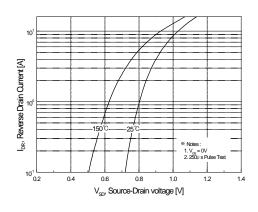


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

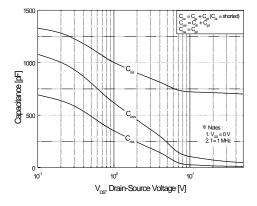


Figure 5. Capacitance Characteristics

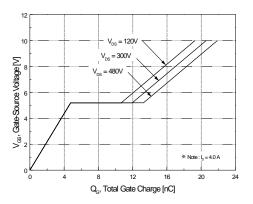


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

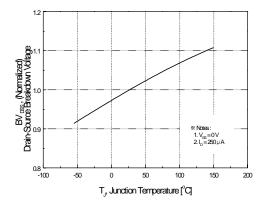
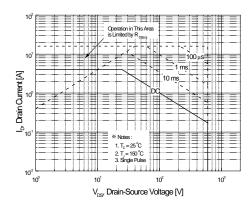


Figure 7. Breakdown Voltage Variation vs Temperature

Figure 8. On-Resistance Variation vs Temperature



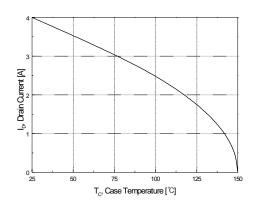


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

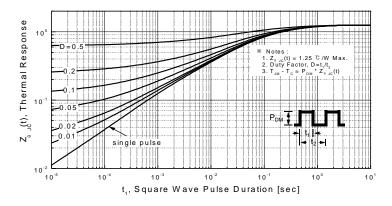
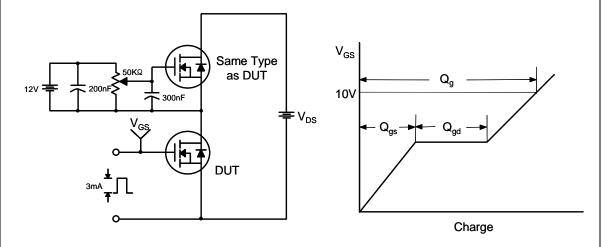


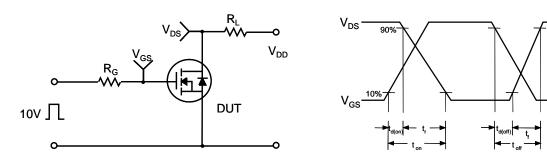
Figure 11. Transient Thermal Response Curve

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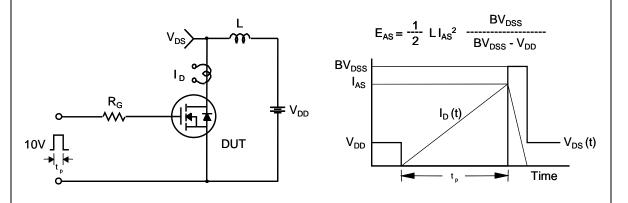
Gate Charge Test Circuit & Waveform



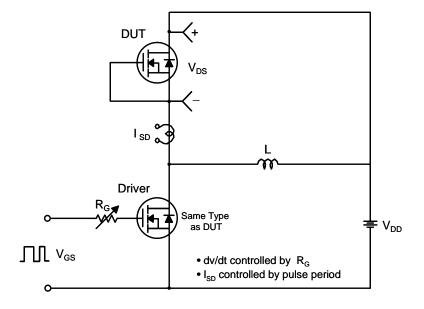
Resistive Switching Test Circuit & Waveforms

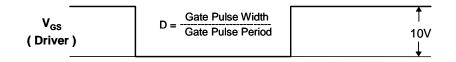


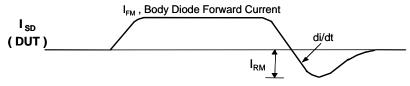
Unclamped Inductive Switching Test Circuit & Waveforms



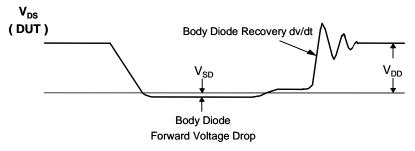
Peak Diode Recovery dv/dt Test Circuit & Waveforms

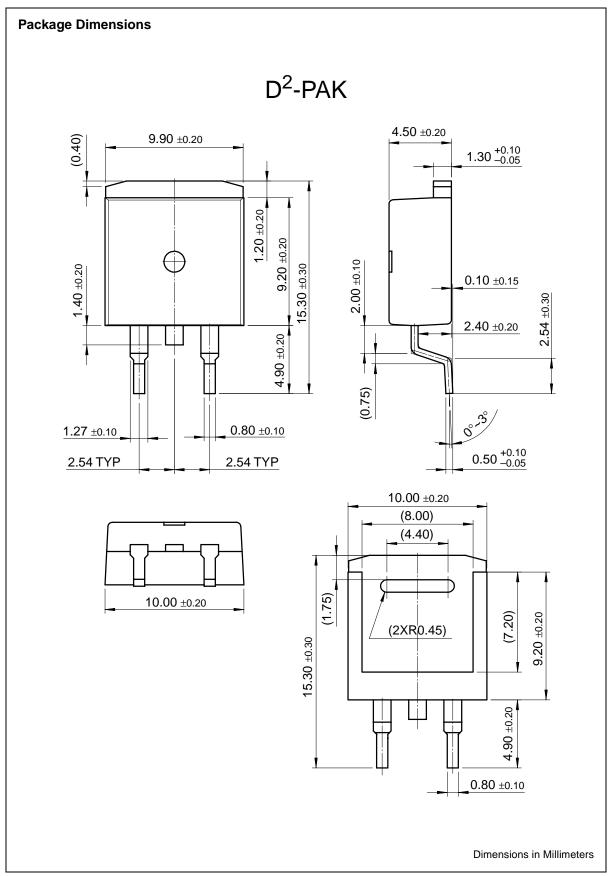


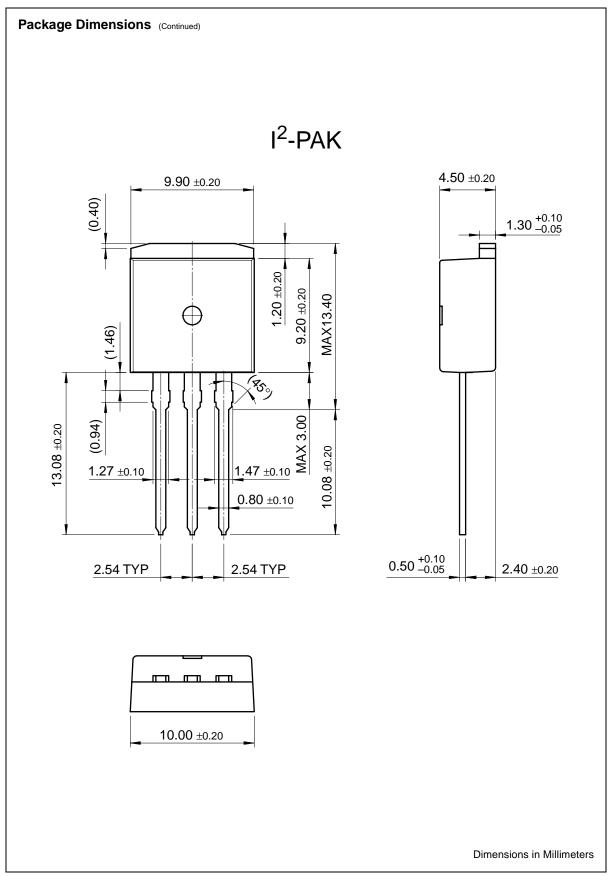




Body Diode Reverse Current







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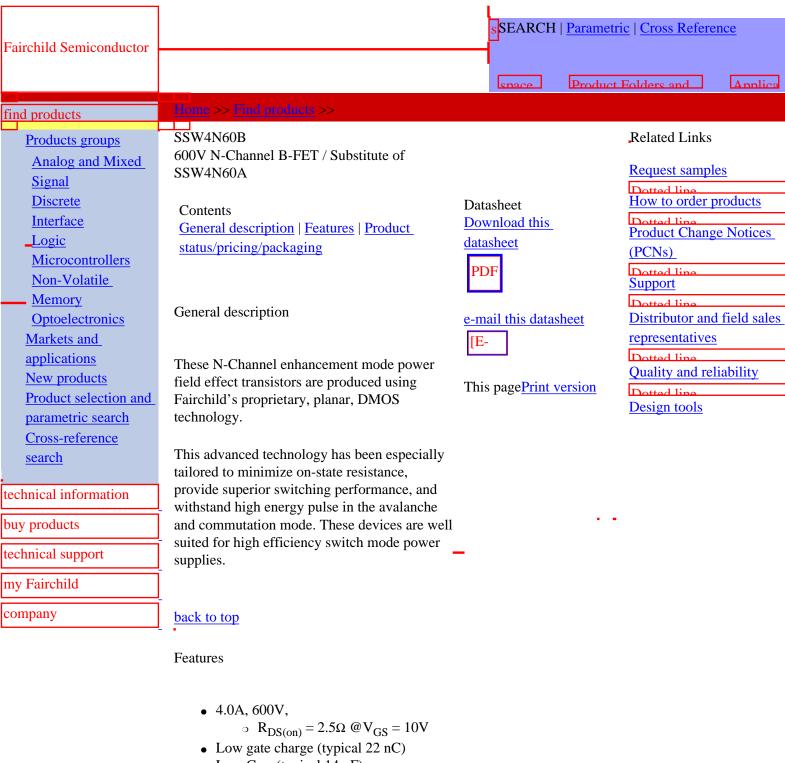
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- Low Crss (typical 14 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

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Product status/pricing/packaging

Product	Product status	Pricing*	Package type	Leads	Packing method

Product Folder - Fairchild P/N SSW4N60B - 600V N-Channel B-FET / Substitute of SSW4N60A

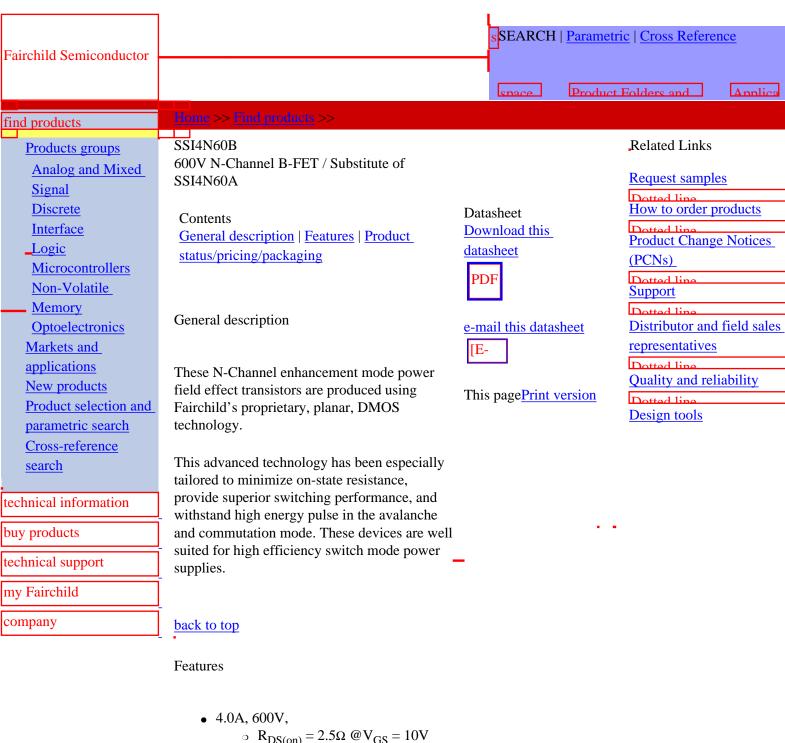
SSW4N60BTM	Full Production	\$0.71	TO-263(D2PAK)	2	TAPE REEL

^{* 1,000} piece Budgetary Pricing

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Product Product status Pricing* Package type Leads Packing method

Product Folder - Fairchild P/N SSI4N60B - 600V N-Channel B-FET / Substitute of SSI4N60A

SSI4N60BTU	Full Production	\$0.71	TO-262(I2PAK)	3	RAIL

^{* 1,000} piece Budgetary Pricing

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